

Notice of References Cited	Application/Control No. 10/840,117	Applicant(s)/Patent Under Reexamination JEN, CHUNG KUEI	
	Examiner Michael Trinh	Art Unit 2822	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-5,764,324	06-1998	Lu et al.	349/113
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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